

Super Junction MOSFET

NCE N-Channel Enhancement Mode Power MOSFET

General Description

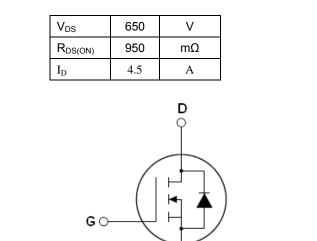
The series of devices use advanced super junction technology and design to provide excellent RDS(ON) with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

Features

- New technology for high voltage device
- Low on-resistance and low conduction losses
- ●small package
- ●Ultra Low Gate Charge cause lower driving requirements
- ●100% Avalanche Tested

Application

- Power factor correction (PFC)
- Switched mode power supplies(SMPS)
- Uninterruptible Power Supply (UPS)



NCE04N65

Pb-Free Product

Schematic diagram

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Package Marking And Ordering Information

Device	Device Package	Marking
NCE04N65	TO-251S	NCE04N65



Table 1. Absolute Maximum Ratings (T_c=25℃)

Parameter	Symbol	NCE04N65	Unit
Drain-Source Voltage (VGs=0V)	Vds	650	V
Gate-Source Voltage (VDs=0V)	Vgs	±30	V
Continuous Drain Current at Tc=25°C	I _{D (DC)}	4.5	А
Continuous Drain Current at Tc=100°C	I _{D (DC)}	2.8	А
Pulsed drain current (Note 1)	DM (pluse)	13.5	А
Drain Source voltage slope, VDS = 480 V, ID = 4.5 A, Tj = 125 °C	dv/dt	50	V/ns
Maximum Power Dissipation(Tc=25°C)	PD	50	W
Derate above 25°C		0.4	W/°C
Single pulse avalanche energy (Note2)	Eas	130	mJ
Avalanche current ^(Note 1)	I _{AR}	4.5	А



°C /W

°C /W

2.5

75

Repetitive Avalanche energy , t_{AR} limited by T_{jmax} (Note 1)	E _{AR}	0.4	mJ		
Operating Junction and Storage Temperature Range	T _J ,T _{STG}	-55+150	°C		
Table 2. Thermal Characteristic					
Parameter	Symbol	NCE04N65	Unit		

 R_{thJC}

 R_{thJA}

Table 3. Electrical Characteristics (TA=25[°]C unless otherwise noted)

Thermal Resistance, Junction-to-Case (Maximum)

Thermal Resistance, Junction-to-Ambient (Maximum)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
On/off states		·	•	•		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA 650				V
Zero Gate Voltage Drain Current(Tc=25℃)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			1	μA
Zero Gate Voltage Drain Current(Tc=125℃)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			50	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±30V,V _{DS} =0V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	2.5	3	3.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =10A		850	950	mΩ
Dynamic Characteristics		·	•	•		
Forward Transconductance	g fs	V _{DS} = 20V, I _D = 2.5A		5		S
Input Capacitance	C _{lss}			480		PF
Output Capacitance	C _{oss}	V _{DS} =100V,V _{GS} =0V, F=1.0MHz		25		PF
Reverse Transfer Capacitance	C _{rss}			2		PF
Total Gate Charge	Qg	V =480V/L =4.5A		19	25	nC
Gate-Source Charge	Q _{gs}	V _{DS} =480V,I _D =4.5A, V _{GS} =10V		2.2		nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V		8.8		nC
Switching times		·	•	•		
Turn-on Delay Time	t _{d(on)}			6		nS
Turn-on Rise Time	tr	V _{DD} =380V,I _D =4.5A,		2.5		nS
Turn-Off Delay Time	t _{d(off)}	R _G =18Ω,V _{GS} =10V		58.5	80	nS
Turn-Off Fall Time	t _f			9.5	14	nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}	T -25°0			4.5	А
Pulsed Source-drain current(Body Diode)	I _{SDM}	T _C =25°C			13.5	А
Forward on voltage	V _{SD}	Tj=25°C,I _{SD} =4.5A,V _{GS} =0V		1	1.3	V
Reverse Recovery Time	t _{rr}			300		nS
Reverse Recovery Charge	Q _{rr}	− Tj=25°C,I _F =4.5A,di/dt=100A/μs		2.6		nC

Notes: 1.Repetitive Rating: Pulse width limited by maximum junction temperature

2. Tj=25°C,VDD=50V,VG=10V, R_G=25\Omega



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

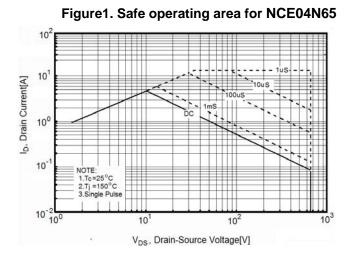


Figure4. Output characteristics

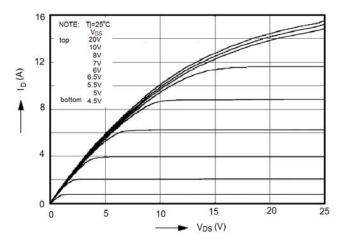


Figure6. Static drain-source on resistance

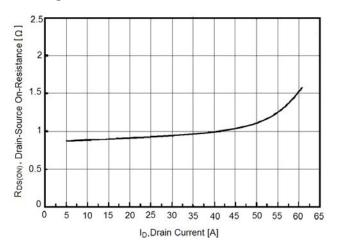


Figure3. Source-Drain Diode Forward Voltage

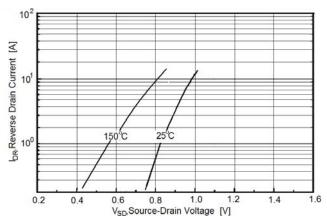


Figure 5. Transfer characteristics

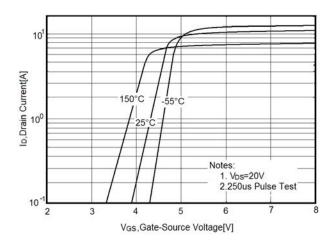


Figure7. R_{DS(ON)} vs Junction Temperature

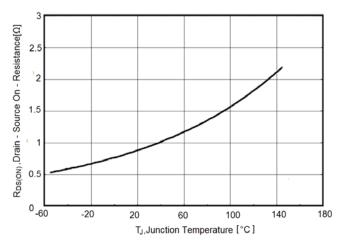




Figure8. BV_{DSS} vs Junction Temperature

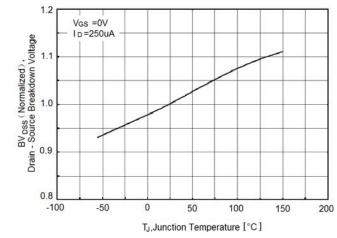


Figure10. Gate charge waveforms

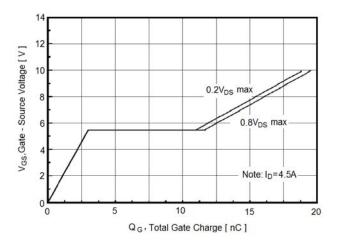


Figure11. Transient Thermal Impedance for NCE04N65

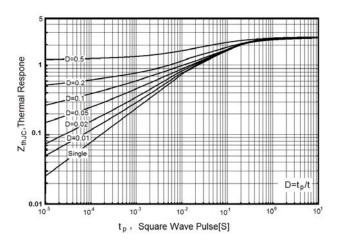


Figure 9. Maximum I_{D} vs Junction Temperature

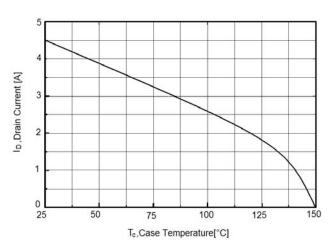
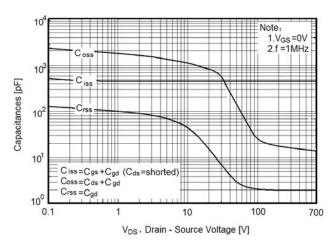


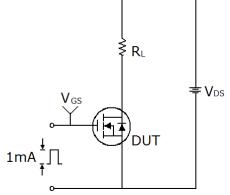
Figure10. Capacitance

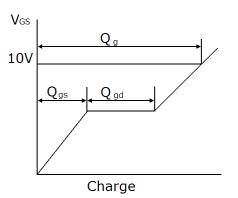




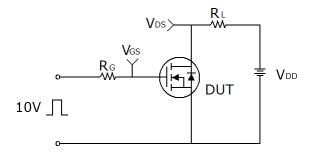
Test circuit

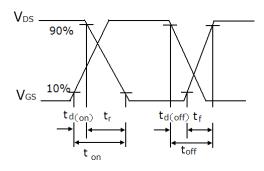
1) Gate charge test circuit & Waveform



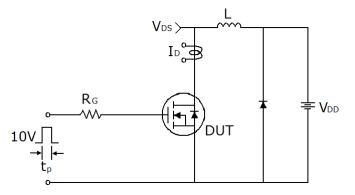


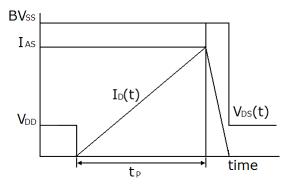
2) Switch Time Test Circuit:





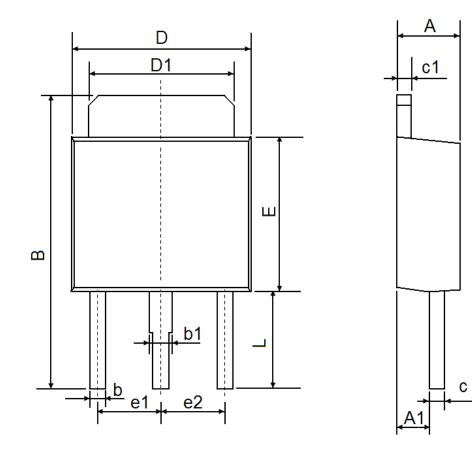
3) Unclamped Inductive Switching Test Circuit & Waveforms







TO-251S Package Information



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max.	
A	2.250	2.350	0.089	0.093	
A1	1.150	1.250	0.045	0.049	
В	10.200	10.800	0.402	0.425	
b	0.550	0.650	0.022	0.026	
b1	0.750	0.850	0.030	0.033	
с	0.480	0.540	0.019	0.021	
c1	0.480	0.540	0.019	0.021	
D	6.400	6.600	0.252	0.260	
D1	5.250	5.350	0.207	0.211	
E	5.400	5.600	0.213	0.220	
e1	2.300 TYP		0.091 TYP		
e2	2.300 TYP		0.091 TYP		
L	3.300	3.700	0.130	0.146	



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